

Abstract Submitted  
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**Electric field control of magnetic semiconductor (Zn,Co)O**  
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Univ. of California, Berkeley — The magnetic transport of a conducting Al(2%)  
doped (Zn,Co)O-field-effect transistor is investigated at low temperature (2-10 K).  
The Al doped (Zn,Co)O channeling layer ( $\sim 26$  nm-thick) was deposited by mag-  
netron sputtering at 550oC and processed into a  $40 \mu\text{m}$  thick Hall bar geometry  
by photolithography and wet etching. An 80nm-thick AlOx layer was deposited at  
room temperature as the insulating barrier and Cr/Au was used as electrodes. The  
Hall effect and sheet resistance were measured from 2 - 10 K as a function of tem-  
perature, magnetic field and gate electric field. For gate electric field  $E=0\text{V}/\text{cm}$ , the  
electron concentration is  $2.58 \times 10^{14}/\text{cm}^2$  at 5 K and there is no anomalous Hall  
effect. This carrier concentration is experimentally shown (by the Hall effect) to  
be tuned by  $\pm 7.0 \times 10^{12}/\text{cm}^2$  with  $E=\pm 4\text{MV}/\text{cm}$ . Application of  $E=+4 \text{ MV}/\text{cm}$   
induces magnetism in the channel layer as seen by an anomalous Hall effect. These  
results show that the magnetic properties of (Zn,Co)O with Al-doping can be mod-  
ulated by gate electric field at low temperature. This research was supported by  
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